

Full Wafer Test System

Single Touchdown 300 mm Full-Wafer Parallel Tester



SYSTEM BENEFITS

- **Flexible Solution for High Throughput Test Floor**
 - ◆ Same system tests memory or logic
 - ◆ Reduces floor space requirements
- **Cost-effective Solution for Single Touchdown Full Wafer Test**
 - ◆ Dramatically reduces test time
 - ◆ Up to 12,000 power channels
 - ◆ Up to 3500 I/O channels (nearly 200,000 device I/O lines using parallel test technology)
 - ◆ Electronics optimized for BIST/DFT testing
- **Production Proven Full-Wafer Tester Solution**
 - ◆ Dozens of systems in production
 - ◆ Protects wafers and probe cards with individual power channel over-current protection
 - ◆ Standard cassette/FOUP automation

“Changing the Way ICs Are Tested”

CORPORATE HEADQUARTERS

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